

**Notice of References Cited**

 Application/Control No.  
 09/911,125

 Applicant(s)/Patent Under  
 Reexamination  
 SEHER ET AL.

 Examiner  
 Brian R. Gordon

 Art Unit  
 1743  
 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-20040196339	10-2004	Kobayashi et al.	347/85
B	US-2004/0176671	09-2004	Fine et al.	600/322
C	US-2004/0129478	07-2004	Breed et al.	180/273
D	US-2002/0092489	07-2002	Mikame et al.	123/90.17
E	US-6,715,465	04-2004	Hallam, Paul W.	123/317
F	US-6,632,651	10-2003	Nevo et al.	435/286.5
G	US-6,623,088	09-2003	Roden et al.	303/113.1
H	US-6,513,902	02-2003	Amano et al.	347/23
I	US-6,168,048	01-2001	Xu et al.	222/1
J	US-5,599,301	02-1997	Jacobs et al.	604/65
K	US-4,780,818	10-1988	Kubo, Jun	701/78
L	US-4,748,564	05-1988	Matsuda, Toshiro	701/79
M	US-6,648,842	11-2003	Horkel, Wilhelm	601/45

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.